



UTRON

Rev 1.7

UT61L1024

128K X 8 BIT HIGH SPEED CMOS SRAM

REVISION HISTORY

REVISION	DESCRIPTION	Released Date
Rev. 1.0	Original.	Apr. 05 2000
Rev. 1.1	Add TSOP-I Package	Aug. 29.2000
Rev. 1.2	Modify the format of power consumption	Sep. 01.2000
Rev. 1.3	1. V_{OH} : 2.4 -> 2.2 2. Input Rise & Fall times : 5->3ns 3. The symbols CE1# ,OE# & WE# are revised as $\overline{CE1}$, $\overline{OE}$ & $\overline{WE}$	Jun. 18,2001
Rev.1.4	Add SOP Package.	Jul. 6,2001
Rev. 1.5	1. Revised TSOP- /STSOP pin configuration typing error : Pin 5= $\overline{WE}$ 、 pin 6=CE2 2. Revised package outline dimension	Apr 16,2002
Rev. 1.6	1. Revised Vcc: Rev. 1.5 : Vcc=3.1V~3.6V Rev. 1.6 : Vcc=3.0V~3.6V 2. Add data retention characteristics and waveforms 3. Revised function block diagram	May 8,2002
Rev. 1.7	1. Add order information for lead free product 2. Revised timing read/write waveform 3. Add $*V_{IL}=-3.0V$ for pulse width less than 10ns into DC table	May 22,2003



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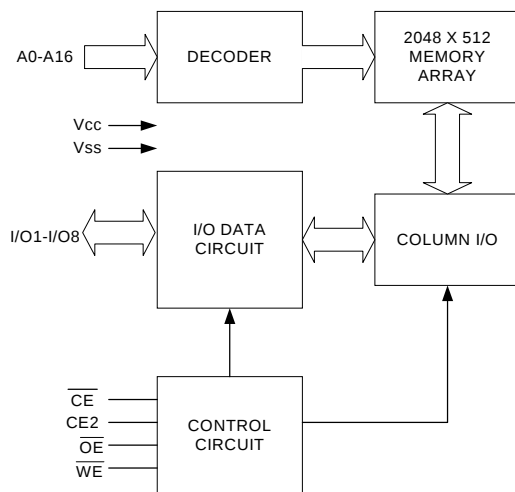
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FEATURES

- Fast access time : 12/15ns (max.)
- Low power operating : 60mA (typ.)
- Single 3.0V~3.6V power supply
- All TTL compatible inputs and outputs
- Fully static operation
- Three state outputs
- Data retention voltage : 2V (min.)
- Package : 32-pin 300 mil skinny PDIP
32-pin 300 mil SOJ
32-pin 450mil SOP
32-pin 8mm x 20mm TSOP-1
32-pin 8mm x 13.4mm STSOP

FUNCTIONAL BLOCK DIAGRAM



PIN DESCRIPTION

SYMBOL	DESCRIPTION
A0 - A16	Address Inputs
I/O1 - I/O8	Data Inputs/Outputs
$\overline{CE}$, CE2	Chip enable 1,2 Inputs
$\overline{WE}$	Write Enable Input
$\overline{OE}$	Output Enable Input
V _{CC}	Power Supply
V _{SS}	Ground
NC	No Connection

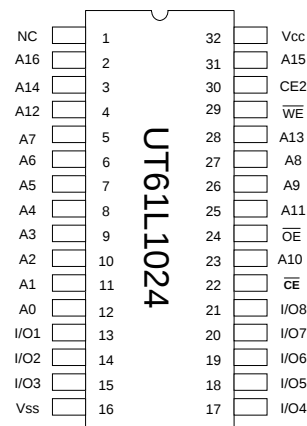
GENERAL DESCRIPTION

The UT61L1024 is a 1,048,576-bit high-speed CMOS static random access memory organized as 131,072 words by 8 bits. It is fabricated using high performance, high reliability CMOS technology.

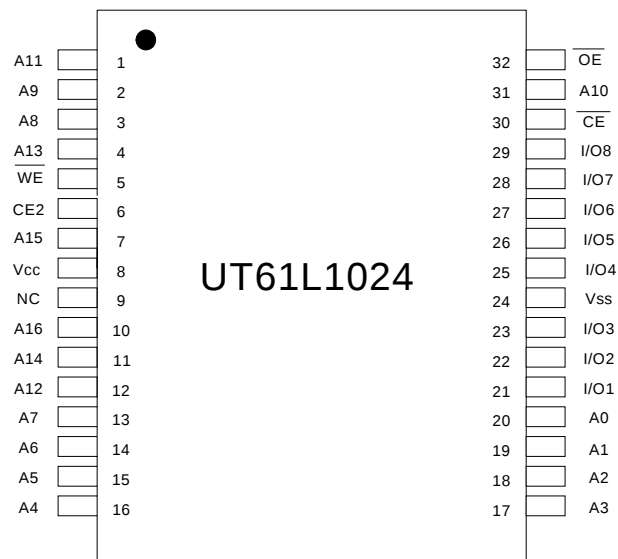
The UT61L1024 is designed for high-speed system applications. It is particularly suited for use in high-density high-speed system applications.

The UT61L1024 operates from a single 3.3V power supply and all inputs and outputs are fully TTL compatible.

PIN CONFIGURATION



PDIP / SOJ/SOP



TSOP-I/STSOP

**ABSOLUTE MAXIMUM RATINGS***

PARAMETER	SYMBOL	RATING	UNIT
Terminal Voltage with Respect to V _{SS}	V _{TERM}	-0.5 to 4.6	V
Operating Temperature	T _A	0 to 70	
Storage Temperature	T _{STG}	-65 to 150	
Power Dissipation	P _D	1	W
DC Output Current	I _{OUT}	50	mA
Soldering Temperature (under 10 sec)	T _{solder}	260	

*Stress greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to the absolute maximum rating conditions for extended period may affect device reliability.

TRUTH TABLE

MODE	$\overline{CE}$	CE2	$\overline{OE}$	$\overline{WE}$	I/O OPERATION	SUPPLY CURRENT
Standby	H	X	X	X	High - Z	I _{SB} , I _{SB1}
Standby	X	L	X	X	High - Z	I _{SB} , I _{SB1}
Output Disable	L	H	H	H	High - Z	I _{CC}
Read	L	H	L	H	D _{OUT}	I _{CC}
Write	L	H	X	L	D _{IN}	I _{CC}

Note: H = V_{IH}, L = V_{IL}, X = Don't care.

DC ELECTRICAL CHARACTERISTICS (V_{CC} = 3.0V 3.6V, T_A = 0 to 70)

PARAMETER	SYMBOL	TEST CONDITION	MIN.	MAX.	UNIT
Power Voltage	V _{CC}		3.0	3.6	V
Input High Voltage	V _{IH}		2.0	V _{CC} +0.5	V
Input Low Voltage	V _{IL}		- 0.5	0.6	V
Input Leakage Current	I _{LI}	V _{SS} V _{IN} V _{CC}	- 1	1	μA
Output Leakage Current	I _{LO}	V _{SS} V _{I/O} V _{CC} $\overline{CE} = V_{IH}$ or CE2 = V _{IL} or $\overline{OE} = V_{IH}$ or $\overline{WE} = V_{IL}$	- 1	1	μA
Output High Voltage	V _{OH}	I _{OH} = - 4mA	2.2	-	V
Output Low Voltage	V _{OL}	I _{OL} = 8mA	-	0.4	V
Operating Power Supply Current	I _{CC}	Cycle time=Min, I _{I/O} = 0mA $\overline{CE} = V_{IL}$, CE2 = V _{IH}	- 12 - 15	100 90	mA
Standby Power Supply Current	I _{SB}	$\overline{CE} = V_{IH}$ or CE2 = V _{IL}	-	20	mA
	I _{SB1}	$\overline{CE} = V_{CC}-0.2V$;or CE2 = 0.2V	-	3	mA

Notes:

1. Overshoot : V_{CC}+3.0v for pulse width less than 8ns.
2. Undershoot : V_{SS}-3.0v for pulse width less than 8ns.
3. Overshoot and Undershoot are sampled, not 100% tested.



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CAPACITANCE ($T_A=25^\circ\text{C}$, $f=1.0\text{MHz}$)

PARAMETER	SYMBOL	MIN.	MAX.	UNIT
Input Capacitance	C_{IN}	-	8	pF
Input/Output Capacitance	$C_{I/O}$	-	10	pF

Note : These parameters are guaranteed by device characterization, but not production tested.

AC TEST CONDITIONS

Input Pulse Levels	0V to 3.0V
Input Rise and Fall Times	3ns
Input and Output Timing Reference Levels	1.5V
Output Load	$C_L=30\text{pF}$, $I_{OH}/I_{OL}=-4\text{mA}/8\text{mA}$

AC ELECTRICAL CHARACTERISTICS ($V_{CC} = 3.0\text{V}$ 3.6V, $T_A = 0^\circ\text{C}$ to 70°C)

(1) READ CYCLE

PARAMETER	SYMBOL	UT61L1024-12		UT61L1024-15		UNIT
		MIN.	MAX.	MIN.	MAX.	
Read Cycle Time	t_{RC}	12	-	15	-	ns
Address Access Time	t_{AA}	-	12	-	15	ns
Chip Enable Access Time	t_{ACE1} , t_{ACE1}	-	12	-	15	ns
Output Enable Access Time	t_{OE}	-	6	-	7	ns
Chip Enable to Output in Low Z	t_{CLZ1*} , t_{CLZ2*}	3	-	4	-	ns
Output Enable to Output in Low Z	t_{OLZ*}	0	-	0	-	ns
Chip Disable to Output in High Z	t_{CHZ1*} , t_{CHZ2*}	-	6	-	7	ns
Output Disable to Output in High Z	t_{OHZ*}	-	6	-	7	ns
Output Hold from Address Change	t_{OH}	3	-	3	-	ns

(2) WRITE CYCLE

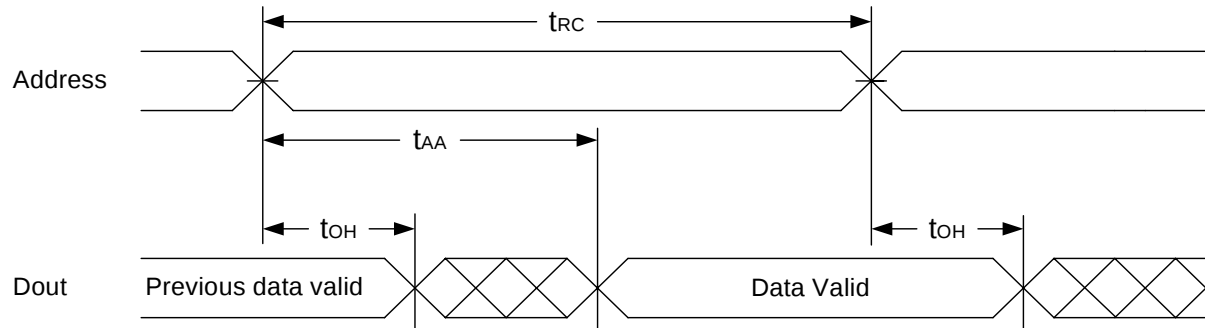
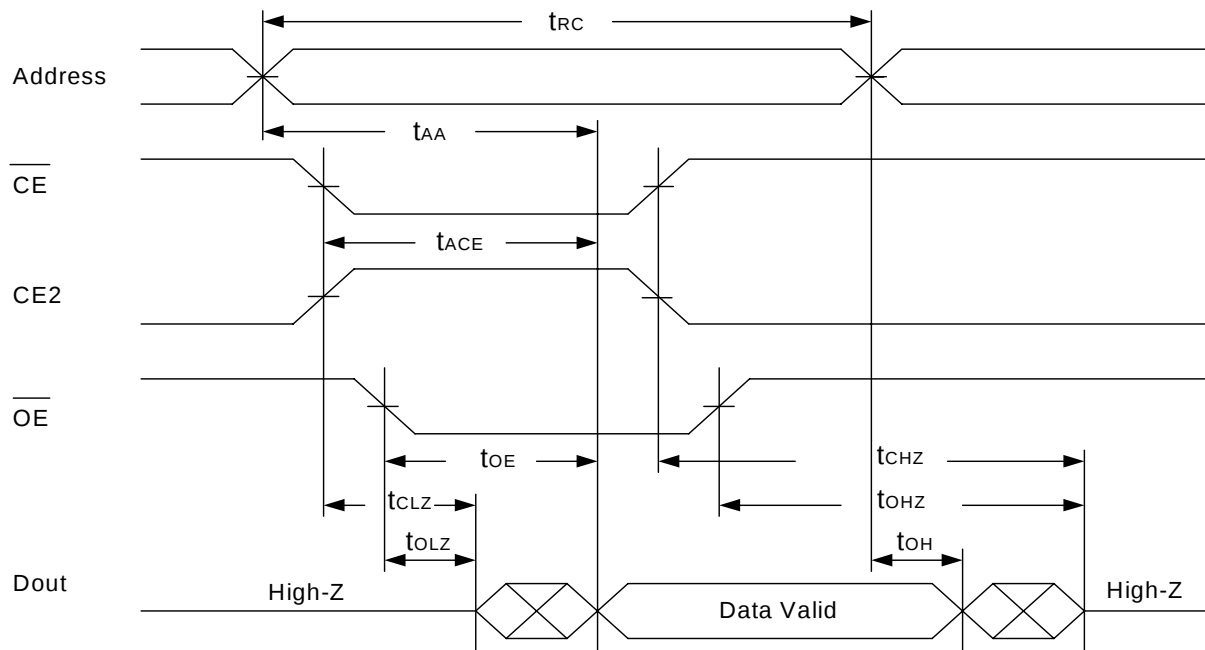
PARAMETER	SYMBOL	UT61L1024-12		UT61L1024-15		UNIT
		MIN.	MAX.	MIN.	MAX.	
Write Cycle Time	t_{WC}	12	-	15	-	ns
Address Valid to End of Write	t_{AW}	10	-	12	-	ns
Chip Enable to End of Write	t_{CW1} , t_{CW2}	10	-	12	-	ns
Address Set-up Time	t_{AS}	0	-	0	-	ns
Write Pulse Width	t_{WP}	9	-	10	-	ns
Write Recovery Time	t_{WR}	0	-	0	-	ns
Data to Write Time Overlap	t_{DW}	7	-	8	-	ns
Data Hold from End of Write Time	t_{DH}	0	-	0	-	ns
Output Active from End of Write	t_{OW*}	3	-	4	-	ns
Write to Output in High Z	t_{WHZ*}	-	7	-	8	ns

*These parameters are guaranteed by device characterization, but not production tested.



TIMING WAVEFORMS

READ CYCLE 1 (Address Controlled) (1,2)

READ CYCLE 2 ($\overline{CE}$ and CE2 and $\overline{OE}$ Controlled) (1,3,4,5)

Notes :

1. $\overline{WE}$ is high for read cycle.
2. Device is continuously selected $\overline{OE}$ =low, $\overline{CE}$ =low, CE2=high.
3. Address must be valid prior to or coincident with $\overline{CE}$ =low, CE2=high; otherwise t_{AA} is the limiting parameter.
4. t_{CLZ} , t_{OLZ} , t_{CHZ} and t_{OHZ} are specified with $C_L=5pF$. Transition is measured $\pm 500mV$ from steady state.
5. At any given temperature and voltage condition, t_{CHZ} is less than t_{CLZ} , t_{OHZ} is less than t_{OLZ} .



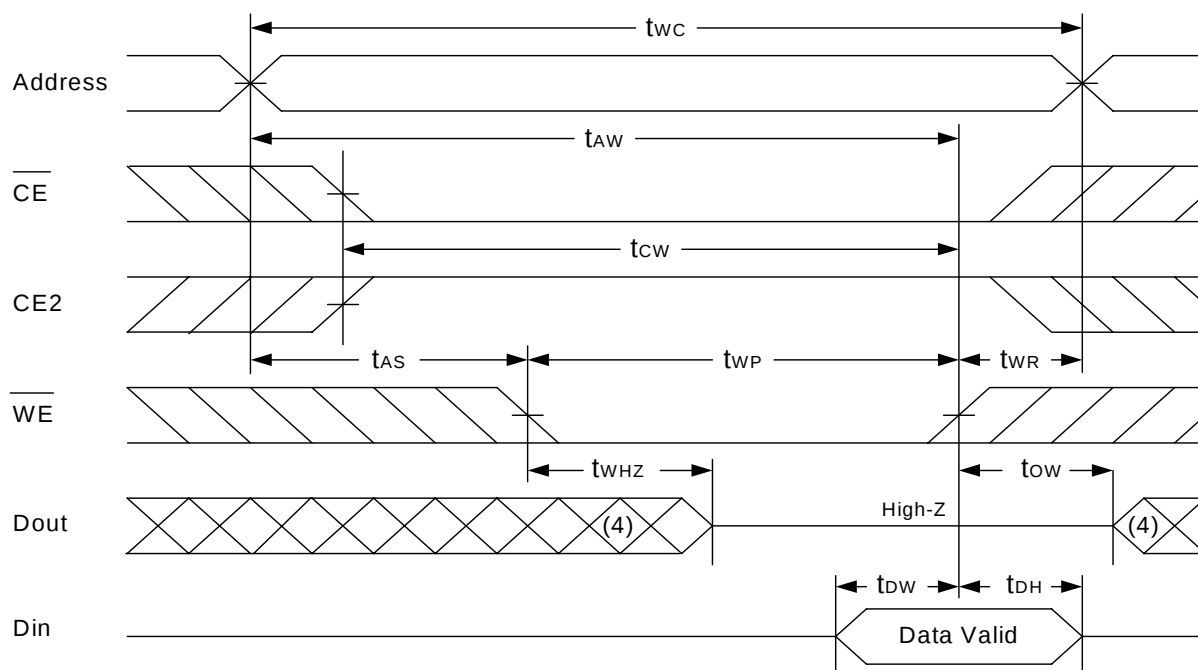
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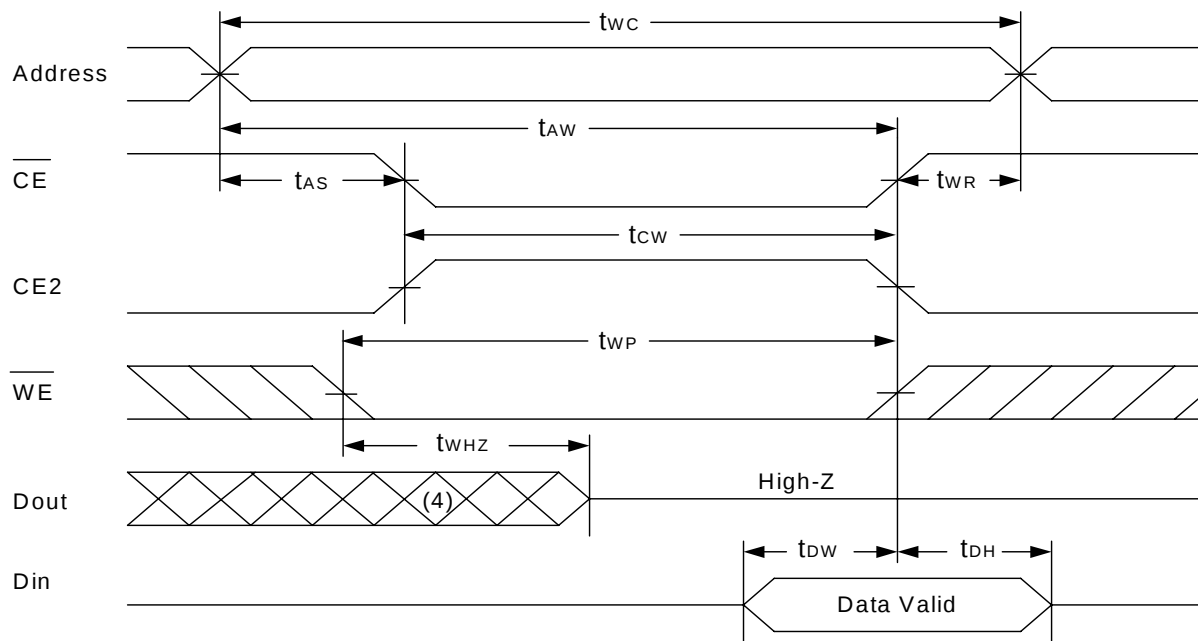
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WRITE CYCLE 1 ($\overline{WE}$ Controlled) (1,2,3,5,6)



WRITE CYCLE 2 ($\overline{CE}$ and CE2 Controlled) (1,2,5,6)





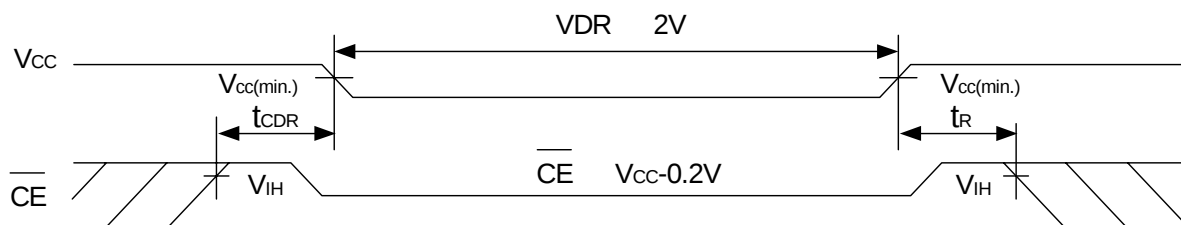
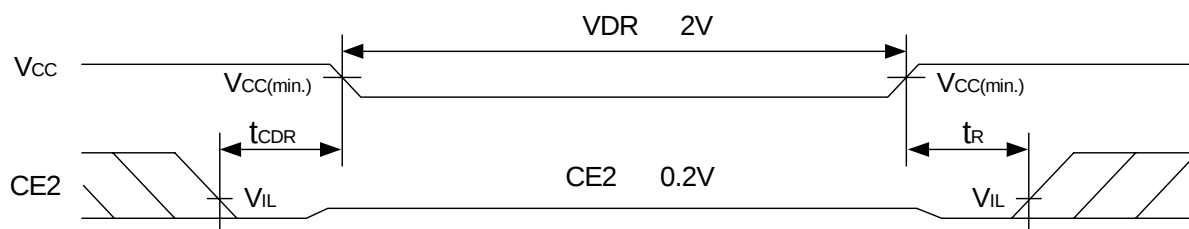
Notes :

1. $\overline{WE}$, $\overline{CE}$ must be high or $\overline{CE2}$ must be low during all address transitions.
2. A write occurs during the overlap of a low $\overline{CE}$, high $\overline{CE2}$, low $\overline{WE}$.
3. During a $\overline{WE}$ controlled write cycle with $\overline{OE}$ low, t_{WP} must be greater than $t_{WHZ} + t_{DW}$ to allow the drivers to turn off and data to be placed on the bus.
4. During this period, I/O pins are in the output state, and input signals must not be applied.
5. If the $\overline{CE}$ low transition and $\overline{CE2}$ high transition occurs simultaneously with or after $\overline{WE}$ low transition, the outputs remain in a high impedance state.
6. t_{OW} and t_{WHZ} are specified with $C_L = 5\text{pF}$. Transition is measured $\pm 500\text{mV}$ from steady state.

DATA RETENTION CHARACTERISTICS ($T_A = 0$ to $+70$)

PARAMETER	SYMBOL	TEST CONDITION	MIN.	MAX.	UNIT
Vcc for Data Retention	V_{DR}	$\overline{CE}$ $V_{CC}-0.2\text{V}$ or $\overline{CE2} \leq 0.2\text{V}$	2.0	3.6	V
Data Retention Current	I_{DR}	$V_{CC}=2\text{V}$ $\overline{CE}$ $V_{CC}-0.2\text{V}$ or $\overline{CE2} \leq 0.2\text{V}$	-	3	mA
Chip Disable to Data Retention Time	t_{CDR}	See Data Retention Waveforms	0	-	ms
Recovery Time	t_R		5	-	ms

DATA RETENTION WAVEFORM

Low Vcc Data Retention Waveform (1) ($\overline{CE}$ controlled)Low Vcc Data Retention Waveform (2) ($\overline{CE2}$ controlled)



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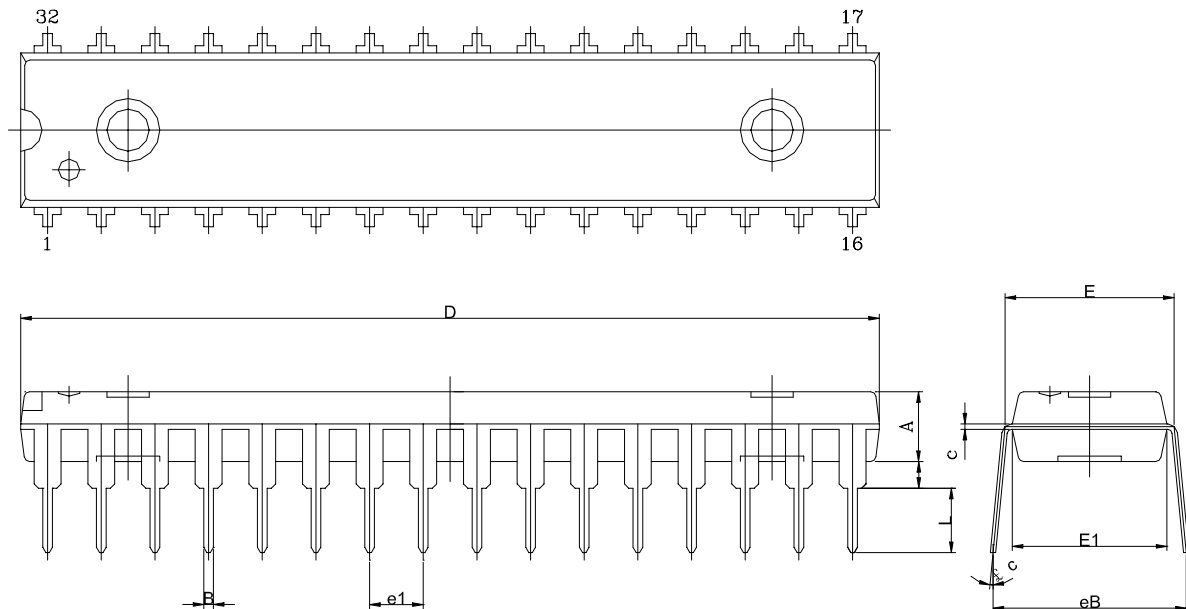
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PACKAGE OUTLINE DIMENSION

32-pin Skinny PDIP Package Outline Dimension



UNIT	INCH(BASE)	MM(REF)
SYMBOL		
A	0.130 ±0.005	3.302 ±0.127
B	0.018 ±0.004	0.457 ±0.102
c	0.010 ±0.004	0.254 ±0.102
D	1.600 ±0.005	40.640 ±0.127
E	0.315 ±0.010	8.001 ±0.254
E1	0.288 ±0.004	7.315 ±0.102
e1	0.100 (TYP)	2.540 (TYP)
eB	0.350 ±0.020	8.890 ±0.508
L	0.125 (MIN)	3.175 (MIN)
xc	0° 10°	0° 10°



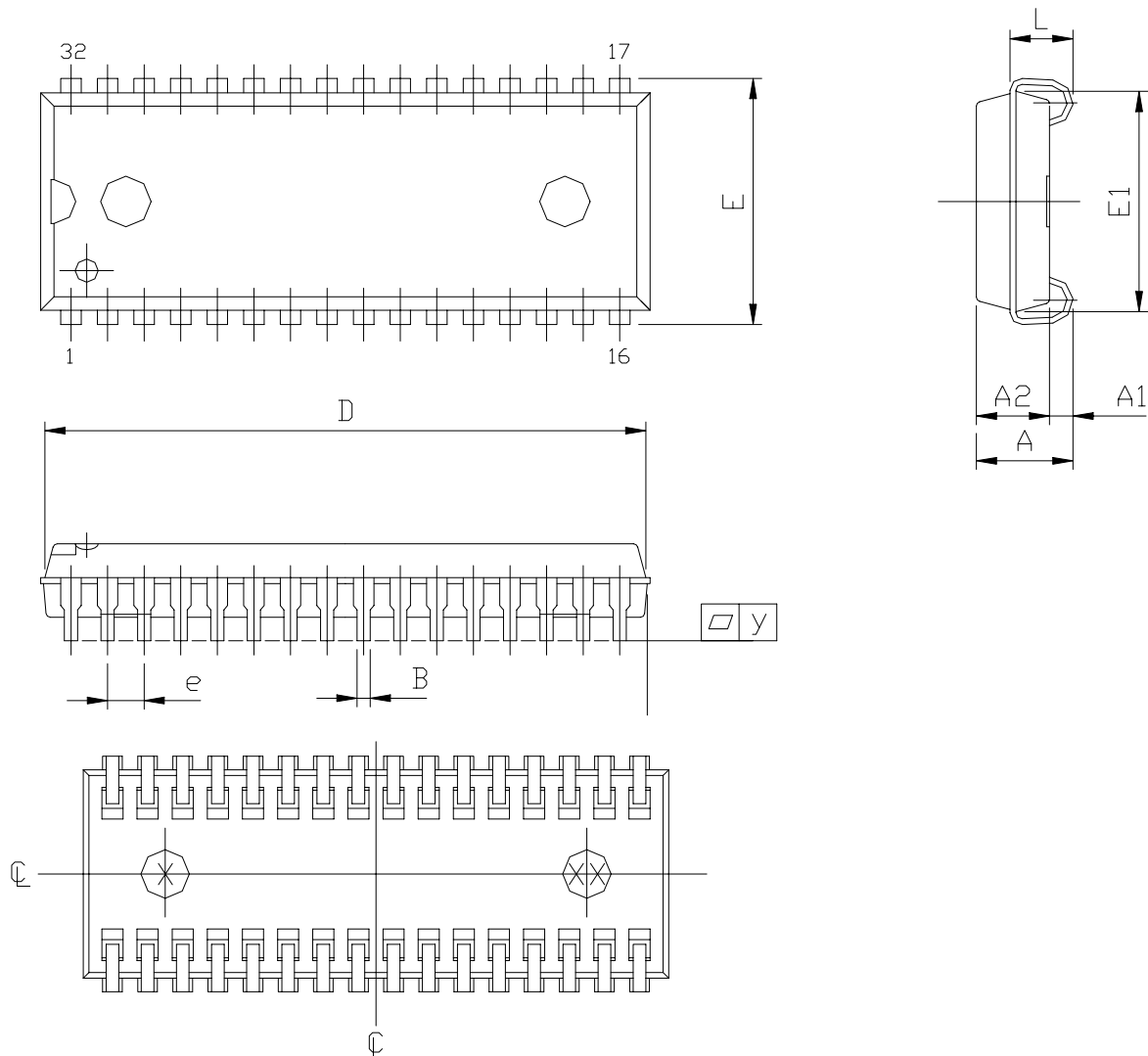
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32-pin 300mil SOJ Package Outline Dimension



SYMBOL \ UNIT	INCH(BASE)	MM(REF)
A	0.148 (MAX)	3.759 (MAX)
A1	0.026 (MIN)	0.660 (MIN)
A2	0.100 ±0.005	2.540 ±0.127
B	0.018 (TYP)	0.457 (TYP)
D	0.830 (MAX)	21.082 (MAX)
E	0.335 (TYP)	8.509 (TYP)
E1	0.300 ±0.005	7.620 ±0.127
e	0.050 (TYP)	1.270 (TYP)
L	0.086 ±0.010	2.184 ±0.254
y	0.003 (MAX)	0.076 (MAX)



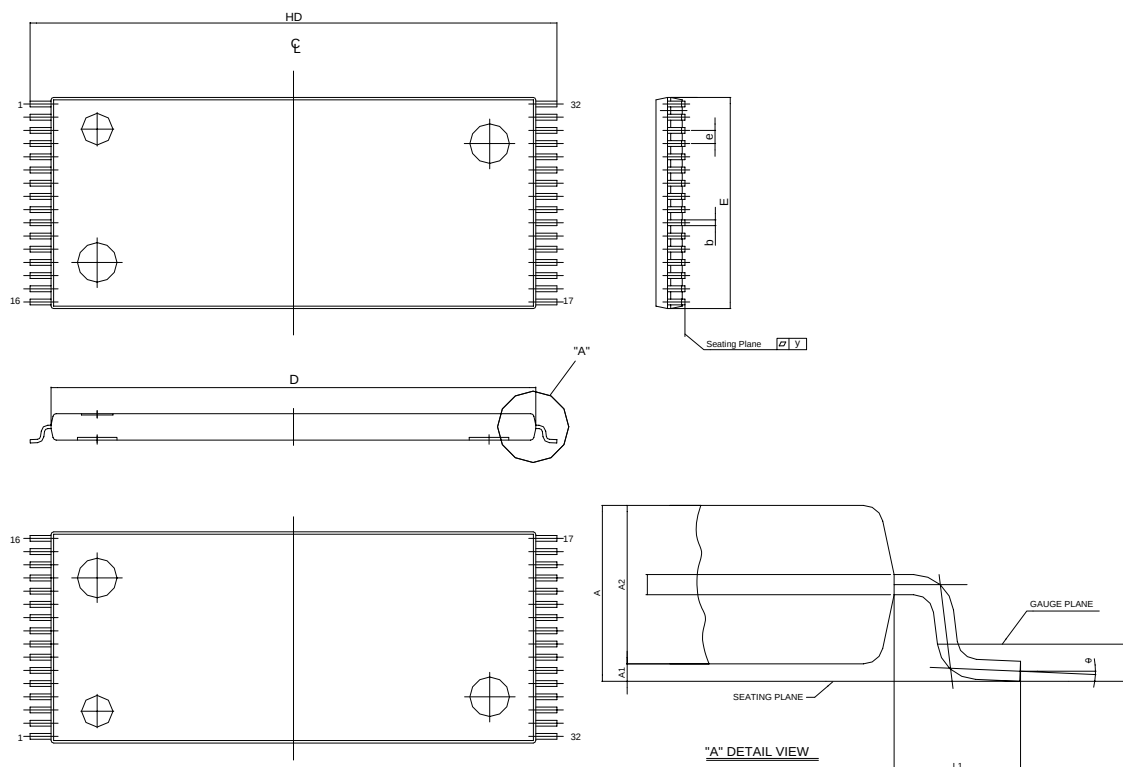
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32-pin 8mm × 20mm TSOP-I Package Outline Dimension



UNIT SYMBOL	INCH(BASE)	MM(REF)
A	0.047 (MAX)	1.20 (MAX)
A1	0.004 ±0.002	0.10 ±0.05
A2	0.039 ±0.002	1.00 ±0.05
b	0.008 + 0.002 - 0.001	0.20 + 0.05 -0.03
D	0.724 ±0.004	18.40 ±0.10
E	0.315 ±0.004	8.00 ±0.10
e	0.020 (TYP)	0.50 (TYP)
HD	0.787 ±0.008	20.00 ±0.20
L1	0.0315 ±0.004	0.80 ±0.10
y	0.003 (MAX)	0.076 (MAX)
Θ	0° 5°	0° 5°



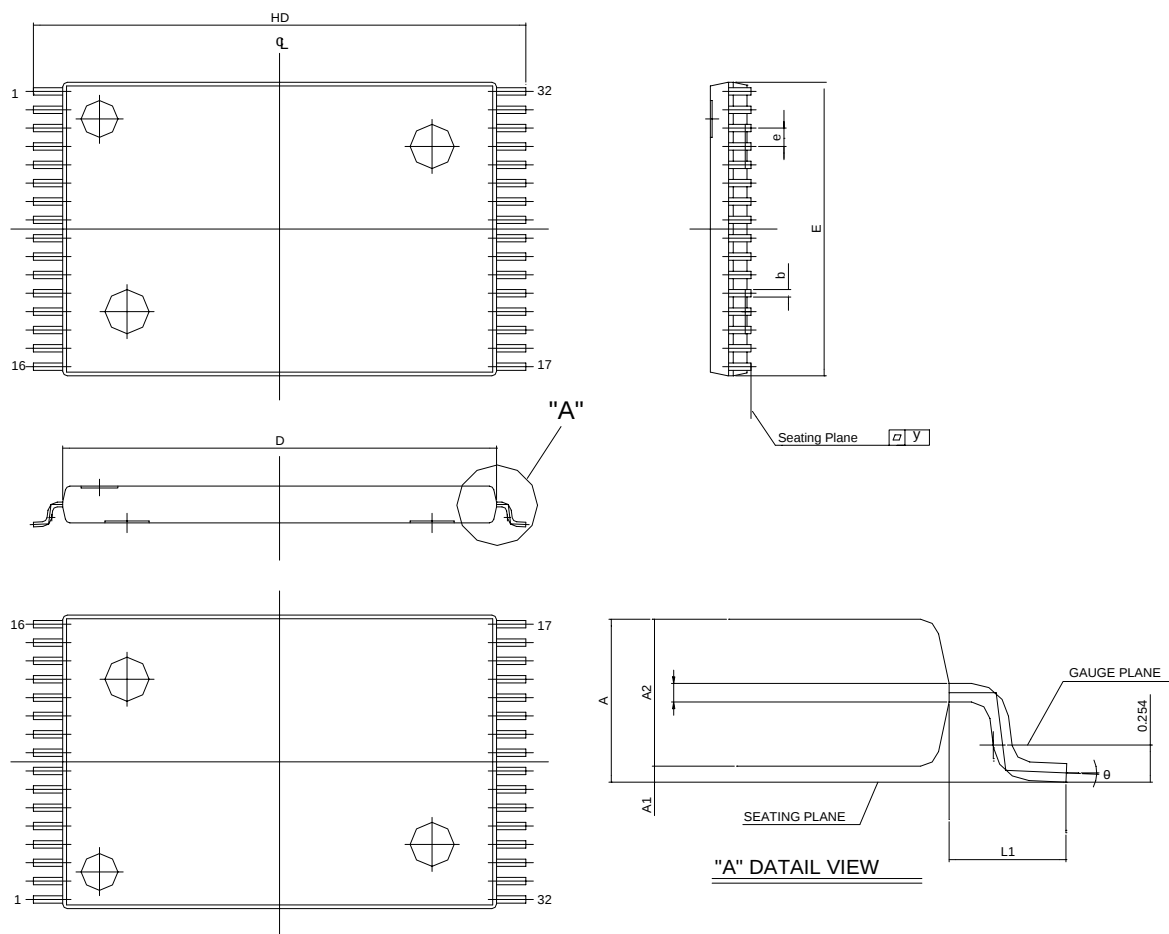
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32-pin 8mm x 13.4mm STSOP Package Outline Dimension



SYMBOL	UNIT	INCH(BASE)	MM(REF)
A		0.047 (MAX)	1.20 (MAX)
A1		0.004 ±0.002	0.10 ±0.05
A2		0.039 ±0.002	1.00 ±0.05
b		0.008 ±0.001	0.200 ±0.025
D		0.465 ±0.004	11.800 ±0.100
E		0.315 ±0.004	8.000 ±0.100
e		0.020 (TYP)	0.50 (TYP)
HD		0.528 ±0.008	13.40 ±0.20.
L1		0.0315 ±0.004	0.80 ±0.10
y		0.003 (MAX)	0.076 (MAX)
Θ		0° 5°	0° 5°



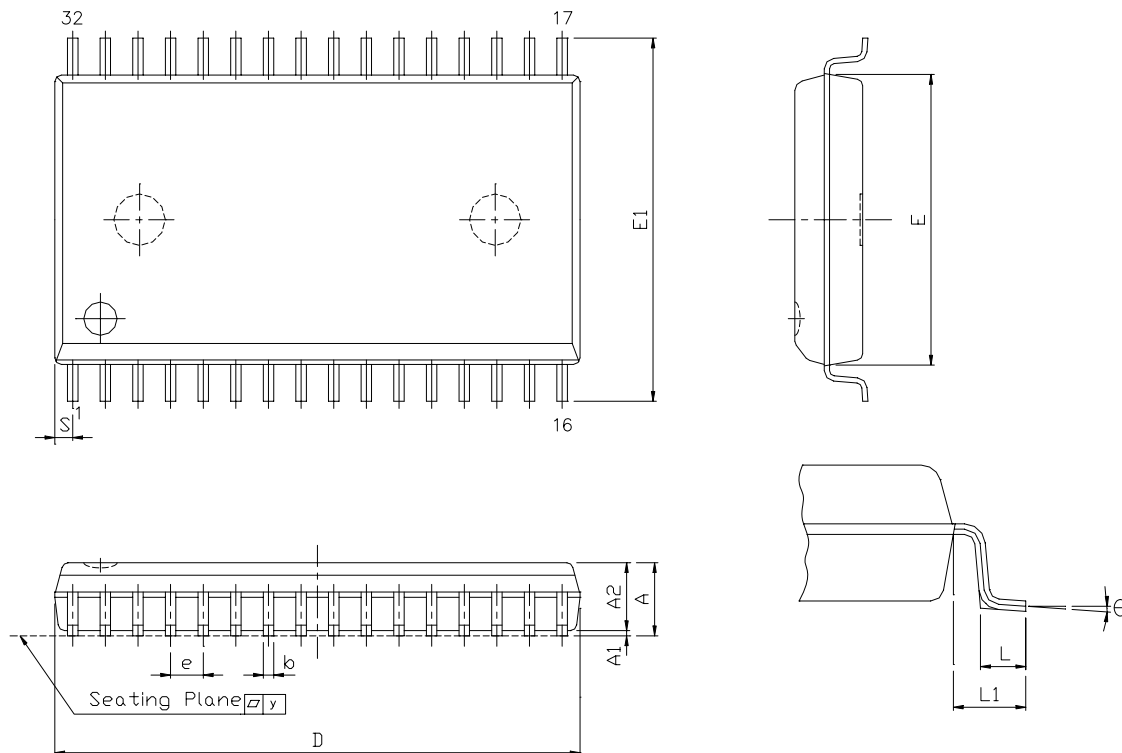
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128K X 8 BIT HIGH SPEED CMOS SRAM

32-pin 450mil SOP Package Outline Dimension



SYMBOL \ UNIT	INCH(BASE)	MM(REF)
A	0.118 (MAX)	2.997 (MAX)
A1	0.004 (MIN)	0.102 (MIN)
A2	0.111 (MAX)	2.82 (MAX)
b	0.016 (TYP)	0.406 (TYP)
D	0.817 (MAX)	20.75 (MAX)
E	0.445 ±0.005	11.303 ±0.127
E1	0.555 ±0.012	14.097 ±0.305
e	0.050 (TYP)	1.270 (TYP)
L	0.0347 ±0.008	0.881 ±0.203
L1	0.055 ±0.008	1.397 ±0.203
S	0.026 (MAX)	0.660 (MAX)
y	0.004 (MAX)	0.101 (MAX)
Θ	0°~10°	0°~10°



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ORDERING INFORMATION

PART NO.	ACCESS TIME (ns)	PACKAGE
UT61L1024KC-12	12	32PIN SKINNY PDIP
UT61L1024KC-15	15	32PIN SKINNY PDIP
UT61L1024JC-12	12	32PIN SOJ
UT61L1024JC-15	15	32PIN SOJ
UT61L1024SC-12	12	32PIN SOP
UT61L1024SC-15	15	32PIN SOP
UT61L1024LC-12	12	32PIN TSOP-1
UT61L1024LC-15	15	32PIN TSOP-1
UT61L1024LS-12	12	32PIN STSOP
UT61L1024LS-15	15	32PIN STSOP

ORDERING INFORMATION (for lead free product)

PART NO.	ACCESS TIME (ns)	PACKAGE
UT61L1024KCL-12	12	32PIN SKINNY PDIP
UT61L1024KCL-15	15	32PIN SKINNY PDIP
UT61L1024JCL-12	12	32PIN SOJ
UT61L1024JCL-15	15	32PIN SOJ
UT61L1024SCL-12	12	32PIN SOP
UT61L1024SCL-15	15	32PIN SOP
UT61L1024LCL-12	12	32PIN TSOP-1
UT61L1024LCL-15	15	32PIN TSOP-1
UT61L1024LSL-12	12	32PIN STSOP
UT61L1024LSL-15	15	32PIN STSOP



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